#### **Features**

- Fast read access time 90ns
- Dual voltage range operation
  - Unregulated battery power supply range, 2.7V to 3.6V, or
  - Standard power supply range,  $5V \pm 10\%$
- Pin compatible with JEDEC standard Atmel<sup>®</sup> AT27C1024
- Low-power CMOS operation
  - $-20\mu\text{A}$  max standby (less than  $1\mu\text{A}$ , typical) for  $V_{CC}=3.6\text{V}$
  - 36mW max active at 5MHz for  $V_{CC} = 3.6V$
- JEDEC standard surface mount package
  - 44-lead PLCC
- High-reliability CMOS technology
  - 2,000V ESD protection
  - 200mA latchup immunity
- Rapid programming algorithm 100µs/word (typical)
- CMOS- and TTL-compatible inputs and outputs
  - JEDEC standard for LVTTL and LVBO
- Integrated product identification code
- Industrial temperature range

#### 1. Description

The Atmel AT27BV1024 is a high-performance, low-power, low-voltage, 1,048,576-bit, one-time programmable, read-only memory (OTP EPROM) organized as 64K by 16 bits. It requires only one supply in the range of 2.7V to 3.6V in normal read mode operation. The x16 organization makes this part ideal for portable and handheld 16- and 32-bit microprocessor-based systems using either regulated or unregulated battery power.

The Atmel innovative design techniques provide fast speeds that rival 5V parts, while keeping the low power consumption of a 3V supply. At  $V_{CC} = 2.7V$ , any word can be accessed in less than 90ns. With a typical power dissipation of only 18mW at 5MHz and  $V_{CC} = 3V$ , the AT27BV1024 consumes less than one-fifth the power of a standard, 5V EPROM.

Standby mode supply current is typically less than  $1\mu A$  at 3V. The AT27BV1024 simplifies system design and stretches battery lifetime even further by eliminating the need for power supply regulation.

The AT27BV1024 is available in an industry-standard, JEDEC-approved, one-time programmable (OTP) PLCC package. All devices feature two-line control  $(\overline{CE}, \overline{OE})$  to give designers the flexibility to prevent bus contention.

The AT27BV1024 operating with  $V_{CC}$  at 3.0V produces TTL-level outputs that are compatible with standard TTL logic devices operating at  $V_{CC} = 5.0$ V. At  $V_{CC} = 2.7$ V, the part is compatible with JEDEC-approved, low-voltage battery operation (LVBO) interface specifications. The device is also capable of standard, 5V operation making it ideally suited for dual supply range systems or card products that are pluggable in both 3V and 5V hosts.

The AT27BV1024 has additional features to ensure high quality and efficient production use. The rapid programming algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100  $\mu$ s/word. The integrated product identification code electronically identifies the device and



1Mb (64K x 16)
Unregulated
Battery Voltage,
High-speed,
One-time
Programmable,
Read-only Memory

Atmel AT27BV1024

0631F-EPROM-4/11



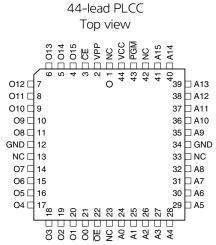


manufacturer. This feature is used by industry-standard programming equipment to select the proper programming algorithms and voltages. The AT27BV1024 programs in exactly the same way as a standard, 5V Atmel AT27C1024, and uses the same programming equipment.

### 2. Pin configurations

Pin Name	Function
A0 - A15	Addresses
O0 - O15	Outputs
CE	Chip enable
ŌĒ	Output enable
PGM	Program strobe
NC	No connect

Note: Both GND pins must be connected.

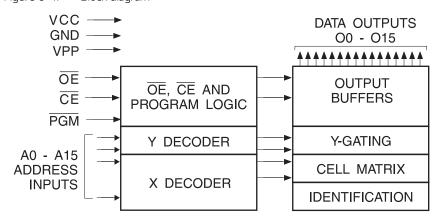


Note: PLCC Package Pins 1 and 23 are "don't connect."

### 3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device non-conformance. At a minimum, a  $0.1\mu\text{F}$ , high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the  $V_{CC}$  and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a  $4.7\mu\text{F}$  bulk electrolytic capacitor should be utilized, again connected between the  $V_{CC}$  and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

Figure 3-1. Block diagram



#### 4. Absolute maximum ratings\*

Temperature under bias	55°C to +125°C
Storage temperature	65°C to +150°C
Voltage on any pin with respect to ground	2.0V to +7.0V <sup>(1)</sup>
Voltage on A9 with respect to ground	-2.0V to +14.0V <sup>(1)</sup>
V <sub>PP</sub> supply voltage with respect to ground	-2.0V to +14.0V <sup>(1)</sup>

\*NOTICE: Stresses beyond those listed under "Absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note:

1. Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is  $V_{CC}$  + 0.75V DC, which may overshoot to +7.0V for pulses of less than 20ns.

#### 5. AC and DC characteristics

Table 5-1. Operating modes

Mode/Pin	Œ	ŌĒ	PGM	Ai	V <sub>PP</sub>	V <sub>CC</sub>	Outputs
Read <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	X <sup>(1)</sup>	Ai	X	V <sub>CC</sub>	D <sub>OUT</sub>
Output disable <sup>(2)</sup>	X	V <sub>IH</sub>	X	X	X	$V_{CC}$	High Z
Standby <sup>(2)</sup>	V <sub>IH</sub>	×	X	X	X <sup>(5)</sup>	V <sub>CC</sub>	High Z
Rapid program <sup>(3)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Ai	V <sub>PP</sub>	V <sub>CC</sub>	D <sub>IN</sub>
PGM verify <sup>(3)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Ai	V <sub>PP</sub>	$V_{CC}$	D <sub>OUT</sub>
PGM inhibit <sup>(3)</sup>	V <sub>IH</sub>	X	X	X	V <sub>PP</sub>	V <sub>CC</sub>	High Z
Product identification <sup>(3)(5)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	X	$A9 = V_{H}^{(4)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A15 = V_{IL}$	V <sub>CC</sub>	V <sub>CC</sub>	ldentification code

Notes:

- 1. X can be  $V_{II}$  or  $V_{IH}$ .
- 2. Read, output disable, and standby modes require 2.7V  $\leq$  V<sub>CC</sub>  $\leq$  3.6V or 4.5V  $\leq$  V<sub>CC</sub>  $\leq$  5.5V.
- 3. Refer to programming characteristics. Programming modes require  $V_{CC} = 6.5V$ .
- 4.  $V_H = 12.0 \pm 0.5 V$ .
- 5. Two identifier words may be selected. All Ai inputs are held low  $(V_{L})$  except A9, which is set to  $V_{H}$ , and A0, which is toggled low  $(V_{\rm IL})$  to select the manufacturer's identification word and high  $(V_{\rm IH})$  to select the device code word.

Table 5-2. DC and AC operating conditions for read oppration

	Atmel AT27BV1024-90
Industrial operating temperature (case)	-40°C - 85°C
V power supply	2.7V to 3.6V
V <sub>CC</sub> power supply	5V ± 10%





Table 5-3. DC and operating characteristics for read operation

Symbol	Parameter	Condition	Min	Max	Units
V <sub>CC</sub> = 2.7V	to 3.6V				
I <sub>LI</sub>	Input load current	$V_{IN} = 0V \text{ to } V_{CC}$		±1	μΑ
I <sub>LO</sub>	Output leakage current	$V_{OUT} = 0V \text{ to } V_{CC}$		±5	μΑ
I <sub>PP1</sub> <sup>(2)</sup>	V <sub>PP</sub> <sup>(1)</sup> read/standby current	$V_{PP} = V_{CC}$		10	μΑ
1	V <sub>CC</sub> <sup>(1)</sup> standby current	$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		20	μΑ
I <sub>SB</sub>	V <sub>CC</sub> Standby current	$I_{SB2}$ (TTL), $\overline{CE} = 2.0 \text{ to } V_{CC} + 0.5V$		100	μΑ
I <sub>CC</sub>	V <sub>CC</sub> active current	$f = 5MHz$ , $I_{OUT} = 0mA$ , $\overline{CE} = V_{IL}$ , $V_{CC} = 3.6V$		8	mA
\/	loout love valtage	V <sub>CC</sub> = 3.0 to 3.6V	-0.6	0.8	V
V <sub>IL</sub>	Input low voltage	V <sub>CC</sub> = 2.7 to 3.6V	-0.6	0.2 x V <sub>CC</sub>	V
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	loout bigb valtage	$V_{CC} = 3.0 \text{ to } 3.6 \text{V}$	2.0	V <sub>CC</sub> + 0.5	V
V <sub>IH</sub>	Input high voltage	V <sub>CC</sub> = 2.7 to 3.6V	0.7 x V <sub>CC</sub>	V <sub>CC</sub> + 0.5	V
		$I_{OL} = 2.0 \text{mA}$		0.4	V
V <sub>OL</sub>	V <sub>OL</sub> Output low voltage	I <sub>OL</sub> = 100μA		0.2	V
		$I_{OL} = 20\mu A$		0.1	V
		$I_{OH} = -2.0 \text{mA}$	2.4		V
V <sub>OH</sub>	Output high voltage	$I_{OH} = -100 \mu A$	V <sub>CC</sub> - 0.2		V
		$I_{OH} = -20\mu A$	V <sub>CC</sub> - 0.1		V
V <sub>CC</sub> = 4.5V	to 5.5V				
ILI	Input load current	$V_{IN} = 0V \text{ to } V_{CC}$		±1	μΑ
I <sub>LO</sub>	Output leakage current	$V_{OUT} = OV \text{ to } V_{CC}$		±5	μΑ
I <sub>PP1</sub> <sup>(2)</sup>	V <sub>PP</sub> <sup>(1)</sup> read/standby current	$V_{PP} = V_{CC}$		10	μΑ
	V <sub>CC</sub> <sup>(1)</sup> standby current	$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μΑ
I <sub>SB</sub>	V <sub>CC</sub> Standby current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5V		1	mΑ
I <sub>cc</sub>	V <sub>CC</sub> active current	$f = 5MHz$ , $I_{OUT} = 0mA$ , $\overline{CE} = V_{IL}$		30	mA
V <sub>IL</sub>	Input low voltage		-0.6	0.8	V
V <sub>IH</sub>	Input high voltage		2.0	V <sub>CC</sub> + 0.5	V
V <sub>OL</sub>	Output low voltage	$I_{OL} = 2.1 \text{mA}$		0.4	V
V <sub>OH</sub>	Output high voltage	Ι <sub>ΟΗ</sub> = -400μΑ	2.4		V

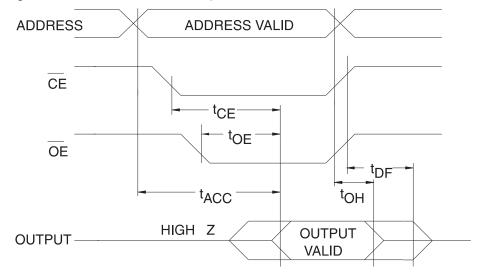
Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$ , and removed simultaneously with or after  $V_{PP}$ .

<sup>2.</sup>  $V_{PP}$  may be connected directly to  $V_{CC}$ , except during programming. The supply current would then be the sum of  $I_{CC}$  and  $I_{PP}$ .

Table 5-4. AC characteristics for read operation

			Atmel AT27BV1024-90		
Symbol	Parameter	Condition	Min	Max	Unit
t <sub>ACC</sub> <sup>(3)</sup>	Address to output delay	CE = OE = V <sub>IL</sub>		90	ns
t <sub>CE</sub> <sup>(2)</sup>	CE to output delay	OE = V <sub>IL</sub>		90	ns
t <sub>OE</sub> <sup>(2)(3)</sup>	OE to output delay	CE = V <sub>IL</sub>		30	ns
t <sub>DF</sub> <sup>(4)(5)</sup>	OE or CE High to output float, whichever occurred first			30	ns
t <sub>OH</sub>	Output hold from address, $\overline{\text{CE}}$ or $\overline{\text{OE}}$ , whichever occurred first		0		ns

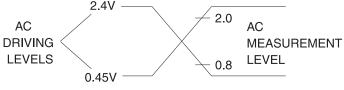
Figure 5-1. AC waveforms for read operation<sup>(1)</sup>



Note: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.

- 2.  $\overline{OE}$  may be delayed up to  $t_{CE}$   $t_{OE}$  after the falling edge of  $\overline{CE}$  without impact on  $t_{CE}$ .
- 3.  $\overline{\text{OE}}$  may be delayed up to  $t_{\text{ACC}}$   $t_{\text{OE}}$  after the address is valid without impact on  $t_{\text{ACC}}$ .
- 4. This parameter is only sampled, and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.
- 6. When reading an Atmel AT27BV1024, a  $0.1\mu F$  capacitor is required across  $V_{CC}$  and ground to suppress spurious voltage transients.

Figure 5-2. Input test waveforms and measurement levels

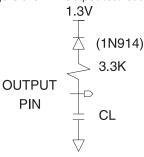


 $t_{\rm R},\,t_{\rm F}$  < 20ns (10% to 90%)





Figure 5-3. Output test load



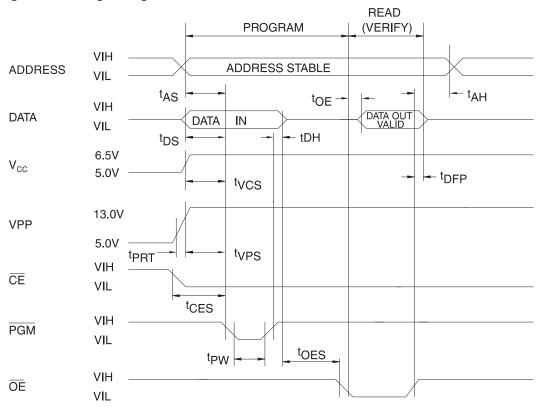
Note: CL = 100pF including jig capacitance.

Table 5-5. Pin capacitance  $f = 1MHz T = 25^{\circ}C^{(1)}$ 

Symbol	Тур	Max	Units	Conditions
C <sub>IN</sub>	4	10	pF	V <sub>IN</sub> = 0V
C <sub>OUT</sub>	8	12	pF	V <sub>OUT</sub> = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.

Figure 5-4. Programming waveforms (1)



Note: 1. The input timing reference is 0.8V for  $V_{\rm IL}$  and 2.0V for  $V_{\rm IH}$ .

- 2.  $t_{OE}$  and  $t_{DEP}$  are characteristics of the device, but must be accommodated by the programmer.
- 3. When programming the Atmel AT27BV1024 a  $0.1\mu F$  capacitor is required across  $V_{pp}$  and ground to suppress spurious voltage transients.

Table 5-6. DC programming characteristics

$$T_A = 25 \pm 5^{\circ} C$$
,  $V_{CC} = 6.5 \pm 0.25 V$ ,  $V_{pp} = 13.0 \pm 0.25 V$ 

			Limits		
Symbol	Parameter	Test conditions	Min	Max	Units
ILI	Input load current	$V_{IN} = V_{IL}, V_{IH}$		±10	μΑ
V <sub>IL</sub>	Input low level		-0.6	0.8	V
V <sub>IH</sub>	Input high level		2.0	V <sub>CC</sub> + 0.1	V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> = 2.1mA		0.4	V
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -400μA	2.4		V
I <sub>CC2</sub>	V <sub>CC</sub> supply current (program and verify)			50	mA
I <sub>PP2</sub>	V <sub>pp</sub> supply current	$\overline{CE} = \overline{PGM} = V_{IL}$		30	mA
V <sub>ID</sub>	A9 product identification voltage		11.5	12.5	V

Table 5-7. AC programming characteristics

 $T_A = 25 \pm 5^{\circ} \text{ C}, V_{CC} = 6.5 \pm 0.25 \text{V}, V_{PP} = 13.0 \pm 0.25 \text{V}$ 

			Lin	Limits		
Symbol Parameter		Test conditions <sup>(1)</sup>	Min	Max	Units	
t <sub>AS</sub>	Address setup time		2		μs	
t <sub>CES</sub>	CE setup time	Input rise and fall times:	2		μs	
t <sub>OES</sub>	OE setup time	(10% to 90%) 20ns	2		μs	
t <sub>DS</sub>	Data setup time	(10/0 to 50/0) 25/15	2		μs	
t <sub>AH</sub>	Address hold time	Input pulse levels:	0		μs	
t <sub>DH</sub>	Data hold time	0.45V to 2.4V  Input timing reference level:	2		μs	
t <sub>DFP</sub>	OE high to output float delay <sup>(2)</sup>		0	130	ns	
t <sub>VPS</sub>	V <sub>PP</sub> setup time	0.8V to 2.0V	2		μs	
t <sub>VCS</sub>	V <sub>CC</sub> setup time		2		μs	
t <sub>PW</sub>	PGM program pulse width <sup>(3)</sup>	Output timing reference level:	95	105	μs	
t <sub>OE</sub>	Data valid from $\overline{\text{OE}}$	0.8V to 2.0V		150	ns	
t <sub>PRT</sub>	V <sub>PP</sub> pulse rise time during programming		50		ns	

Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously with or after  $V_{PP}$ .

- 2. This parameter is only sampled, and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.
- 3. Program pulse width tolerance is  $100\mu \sec \pm 5\%$ .

Table 5-8. The Atmel AT27BV1024 integrated product identification code<sup>(1)</sup>

		Pins									
Codes	A0	O15- O8	07	06	O5	04	03	02	01	00	Hex data
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device type	1	0	1	1	1	1	0	0	0	1	00F1

Note: 1. The Atmel AT27BV1024 has the same product identification code as the Atmel AT27C1024. Both are programming compatible

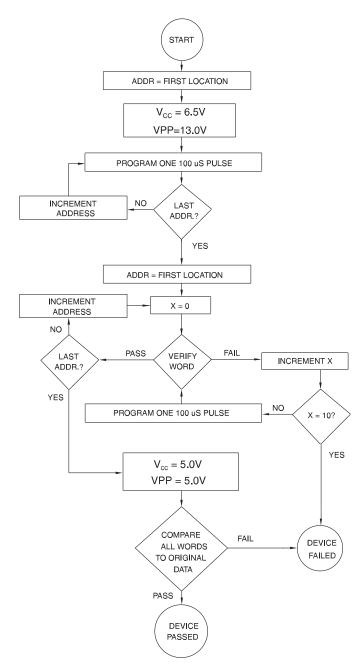




### 6. Rapid programming algorithm

A 100 $\mu$ s  $\overline{PGM}$  pulse width is used to program. The address is set to the first location.  $V_{CC}$  is raised to 6.5V and  $V_{PP}$  is raised to 13.0V. Each address is first programmed with one 100 $\mu$ s  $\overline{PGM}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 100 $\mu$ s pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked.  $V_{PP}$  is then lowered to 5.0V and  $V_{CC}$  to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.

Figure 6-1. Rapid programming algorithm



## 7. Ordering information

# Green package (Pb/hailde-free)

t <sub>ACC</sub>	I <sub>CC</sub> (mA)					
(ns)	Active	Standby	Atmel ordering code	Lead finish	Package	Operation range
90	8	0.02	AT27BV1024-90JU	Matte tin	44J	Industrial (-40°C to 85°C)

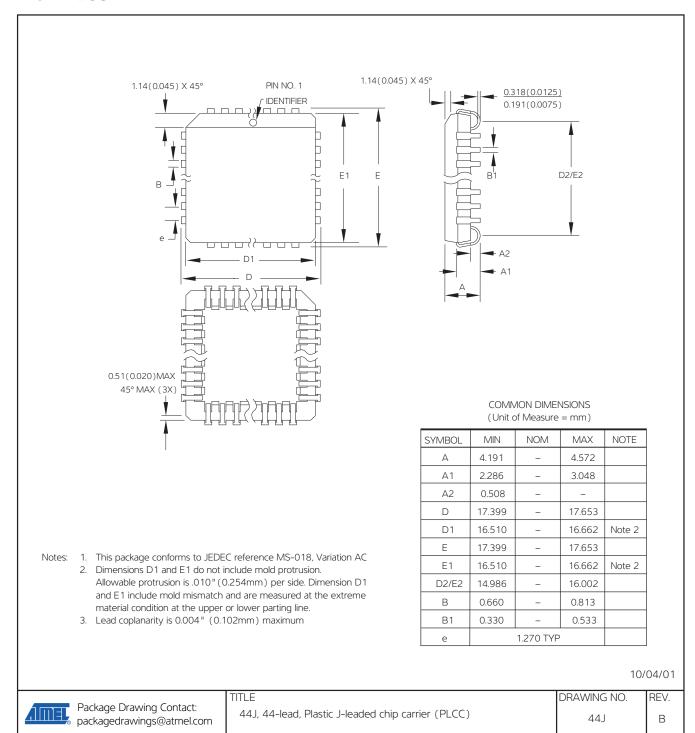
	Package type
44J 44-lead, plastic, J-leaded chip carrier (PLCC)	





## 8. Packaging Information

## 44J – PLCC



## 9. Revision history

Doc. rev.	Date	Comments
		Remove VSOP package
0631F	04/2011	Add lead finish to ordering information
		Change 120ns to 90ns
0631E	12/2007	





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